



Reel No.: 52775-024

IPD

PATENT

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of : Customer Number: 20277  
Masahiro NAKAYAMA, et al. : Confirmation Number: 1716  
Serial No.: 10/662,524 : Group Art Unit: 2826  
Filed: September 16, 2003 : Examiner: not yet assigned  
For: CHAMFERED FREESTANDING NITRIDE SEMICONDUCTOR WAFER AND  
METHOD OF CHAMFERING NITRIDE SEMICONDUCTOR WAFER

**INFORMATION DISCLOSURE STATEMENT**

Mail Stop Amendments  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached form PTO-1449. It is respectfully requested that the references be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

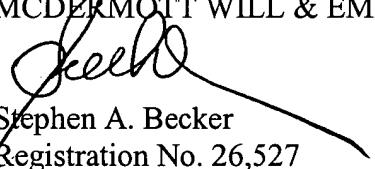
This Information Disclosure Statement is being filed within three months of the U.S. filing date OR before the mailing date of a first Office Action on the merits. No certification or fee is required.

Each non-English language reference was first cited in a corresponding foreign application search report or office action and its relevance discussed therein. A copy of the foreign search report or office action, is attached for the Examiner's information.

Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account 500417 and please credit any excess fees to such deposit account.

Respectfully submitted,

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**Date: August 10, 2004**



SHEET 1 OF 1

<b>INFORMATION DISCLOSURE CITATION IN AN APPLICATION</b>  <b>(PTO-1449)</b>			ATTY. DOCKET NO. <b>52775-024</b>	SERIAL NO. <b>10/662,524</b>		
			<b>APPLICANT</b> <b>Masahiro NAKAYAMA, et al.</b>			
			FILING DATE <b>September 16, 2003</b>	GROUP <b>2826</b>		
<b>U.S. PATENT DOCUMENTS</b>						
EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code <sub>2</sub> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document		
A1	US	2002/0098787	07/25/2002	Kunisawa et al.		
B1	US	6,410,438	06/25/2002	Ozaki		
B1	US	6,402,596	06/11/2002	Hakomori et al.		
A1	US	2002/0068201	06/06/2002	Vaudo et al.		
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<b>FOREIGN PATENT DOCUMENTS</b>						
EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Code <sub>3</sub> -Number +-Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation
A1		EP 1 034 883	09/13/2000	Nippei Toyama Corp.		Yes
A2		EP 1 120 191	08/01/2001	TSK America. Inc.		No
<b>OTHER ART</b> (Including Author, Title, Date, Pertinent Pages, Etc.)						
EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.				
<b>EXAMINER</b>			<b>DATE CONSIDERED</b>			

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1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.